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Application/Control No.	Applicant(s)/Patent under Reexamination
10/083,136	CHERIAN ET AL.
Examiner	Art Unit

Jamal A. Fox

2664

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Class	Subclass	Date	Examiner
370	328, 216, 217, 218, 221, 254	3/6/2006	JFOX
370	229, 231	3/6/2006	JFOX
370	235, 237	3/6/2006	JFOX
370	242, 363	3/6/2006	JFOX
370	374, 378	3/6/2006	JFOX
455	422.1	3/6/2006	JFOX
455	460	3/6/2006	JFOX
455	524-525	3/6/2006	JFOX
714	712, 4, 6	3/6/2006	JFOX
714	10, 43	3/6/2006	JFOX
714	44, 7, 48	3/6/2006	JFOX
710	15, 302	3/6/2006	JFOX
710	1, 2, 8	3/6/2006	JFOX
710	29	3/6/2006	JFOX

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
·	DATE	EXMR
See East Search History	3/6/2006	JFOX
See Inventor Name Search Result	3/7/2006	JFOX
See IEEE NPL Search History	3/7/2006	JFOX
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Search	Notes	(continue	d)
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Class	Subclass	Date	Examiner
710	36-38, 51, 62-64, 72- 74	3/6/2006	JFOX
710	305-317	3/6/2006	JFOX
710	104, 300	3/6/2006	JFOX
710	301-304	3/6/2006	JFOX
709	239, 105	3/6/2006	JFOX
709	213, 325	3/6/2006	JFOX .
709	1, 104	3/6/2006	JFOX
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709	209, 2	3/6/2006	JFOX
711	6, 203	3/6/2006	JFOX
711	114, 100	3/6/2006	JFOX
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